Application/Control No. Applicant(s)/Pat Reexamination

Notice of References Cited

Application/Control No. 09/888,912	Applicant(s)/Pater Reexamination CHOI ET AL.	nt Under
Examiner	Art Unit	_
Yvette C. Thornton	1752	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2002/0195419 A1	12-2002	PAVELCHEK, EDWARD K.	216/16
	В	US-6,486,283 B2	11-2002	Hong et al.	526/328.5
	С	US-6,368,768 B1	04-2002	Jung et al.	430/270.1
	D	US-6,316,165 B1	11-2001	Pavelchek et al.	430/311
	Е	US-6,045,970 A	04-2000	Choi, Sang-jun	430/270.1
	F	US-5,178,982 A	01-1993	Kato et al.	430/96
	G	US-4,117,239 A	09-1978	Stolka et al.	560/221
	H	US-			
	-	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 05024951 A	02-1993	Japan	IRIE et al.	C04B 40/00
	0					
	Р					
	Q					
	R					
	s	V				
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.